



Docket No.: 06920/000K024-US0
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yasuyuki Inoue

Application No.: 10/037,696

Confirmation No.: 7564

Filed: November 9, 2001

Art Unit: 2133

For: SEMICONDUCTOR TEST APPARATUS

Examiner: J. P. Trimmings

AMENDMENT AFTER FINAL ACTION (37 C.F.R. SECTION 1.116)

MS AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

*OK to enter
per RCE 6-21-05
pay*

INTRODUCTORY COMMENTS

In response to the Office Action dated January 27, 2005 (Paper No. 01102005), and subject to the approval of the Examiner, please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.